

Notice of References Cited	Application/Control No. 10/564,742		Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner JACOB MARKS		Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,569,569	05-2003	Kweon et al.	429/231.1
*	B	US-7,393,476	07-2008	Shiozaki et al.	252/521.2
*	C	US-6,291,103	09-2001	Park et al.	429/231.95
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03044881	05-2003		Shiozaki et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.